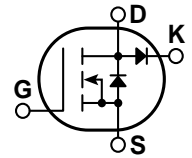


### POWER MOS 7® MOSFET

Power MOS 7® is a new generation of low loss, high voltage, N-Channel enhancement mode power MOSFETS. Both conduction and switching losses are addressed with Power MOS 7® by significantly lowering  $R_{DS(ON)}$  and  $Q_g$ . Power MOS 7® combines lower conduction and switching losses along with exceptionally fast switching speeds inherent with APT's patented metal gate structure.



- Lower Input Capacitance
- Lower Miller Capacitance
- Lower Gate Charge,  $Q_g$
- Increased Power Dissipation
- Easier To Drive
- PFC "Boost" Configuration




#### MAXIMUM RATINGS

All Ratings:  $T_C = 25^\circ\text{C}$  unless otherwise specified.

Symbol	Parameter	APT5010JLL	UNIT
$V_{DSS}$	Drain-Source Voltage	500	Volts
$I_D$	Continuous Drain Current @ $T_C = 25^\circ\text{C}$	44	Amps
$I_{DM}$	Pulsed Drain Current <sup>①</sup>	176	
$V_{GS}$	Gate-Source Voltage Continuous	$\pm 30$	Volts
$V_{GSM}$	Gate-Source Voltage Transient	$\pm 40$	
$P_D$	Total Power Dissipation @ $T_C = 25^\circ\text{C}$	446	Watts
	Linear Derating Factor	3.57	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$T_L$	Lead Temperature: 0.063" from Case for 10 Sec.	300	
$I_{AR}$	Avalanche Current <sup>①</sup> (Repetitive and Non-Repetitive)	44	Amps
$E_{AR}$	Repetitive Avalanche Energy <sup>①</sup>	50	mJ
$E_{AS}$	Single Pulse Avalanche Energy <sup>④</sup>	1600	

#### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-Source Breakdown Voltage ( $V_{GS} = 0V, I_D = 250\mu\text{A}$ )	500			Volts
$I_{D(on)}$	On State Drain Current <sup>②</sup> ( $V_{DS} > I_{D(on)} \times R_{DS(on)}$ Max, $V_{GS} = 10V$ )	44			Amps
$R_{DS(on)}$	Drain-Source On-State Resistance <sup>②</sup> ( $V_{GS} = 10V, 22A$ )			0.100	Ohms
$I_{DSS}$	Zero Gate Voltage Drain Current ( $V_{DS} = 500V, V_{GS} = 0V$ )			100	$\mu\text{A}$
	Zero Gate Voltage Drain Current ( $V_{DS} = 400V, V_{GS} = 0V, T_C = 125^\circ\text{C}$ )			500	
$I_{GSS}$	Gate-Source Leakage Current ( $V_{GS} = \pm 30V, V_{DS} = 0V$ )			$\pm 100$	nA
$V_{GS(th)}$	Gate Threshold Voltage ( $V_{DS} = V_{GS}, I_D = 2.5\text{mA}$ )	3		5	Volts

 **CAUTION:** These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

APT Website - <http://www.advancedpower.com>

## DYNAMIC CHARACTERISTICS

APT5010JLLU2

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1\text{ MHz}$		4360		pF
$C_{oss}$	Output Capacitance			894		
$C_{rss}$	Reverse Transfer Capacitance			60		
$Q_g$	Total Gate Charge ③	$V_{GS} = 10V$ $V_{DD} = 250V$ $I_D = 44A @ 25^\circ C$		96		nC
$Q_{gs}$	Gate-Source Charge			24		
$Q_{gd}$	Gate-Drain ("Miller") Charge			49		
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = 15V$ $V_{DD} = 250V$ $I_D = 44A @ 25^\circ C$ $R_G = 0.6\Omega$		11		ns
$t_r$	Rise Time			15		
$t_{d(off)}$	Turn-off Delay Time			25		
$t_f$	Fall Time			3		

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$I_S$	Continuous Source Current (Body Diode)			44	Amps
$I_{SM}$	Pulsed Source Current ① (Body Diode)			176	
$V_{SD}$	Diode Forward Voltage ② ( $V_{GS} = 0V, I_S = -I_D 44A$ )			1.3	Volts
$t_{rr}$	Reverse Recovery Time ( $I_S = -I_D 44A, di_S/dt = 100A/\mu s$ )		608		ns
$Q_{rr}$	Reverse Recovery Charge ( $I_S = -I_D 44A, di_S/dt = 100A/\mu s$ )		10.86		$\mu C$
$dv/dt$	Peak Diode Recovery $dv/dt$ ⑤			8	V/ns

## THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.28	$^\circ C/W$
$R_{\theta JA}$	Junction to Ambient			40	

① Repetitive Rating: Pulse width limited by maximum junction temperature

② Pulse Test: Pulse width < 380  $\mu s$ , Duty Cycle < 2%

③ See MIL-STD-750 Method 3471

APT Reserves the right to change, without notice, the specifications and information contained herein.

④ Starting  $T_j = +25^\circ C$ ,  $L = 1.65mH$ ,  $R_G = 25\Omega$ , Peak  $I_L = 44A$

⑤  $dv/dt$  numbers reflect the limitations of the test circuit rather than the device itself.  $I_S = -I_D 44A$   $di/dt \leq 700A/\mu s$   $V_R \leq V_{DSS}$   $T_j \leq 150^\circ C$

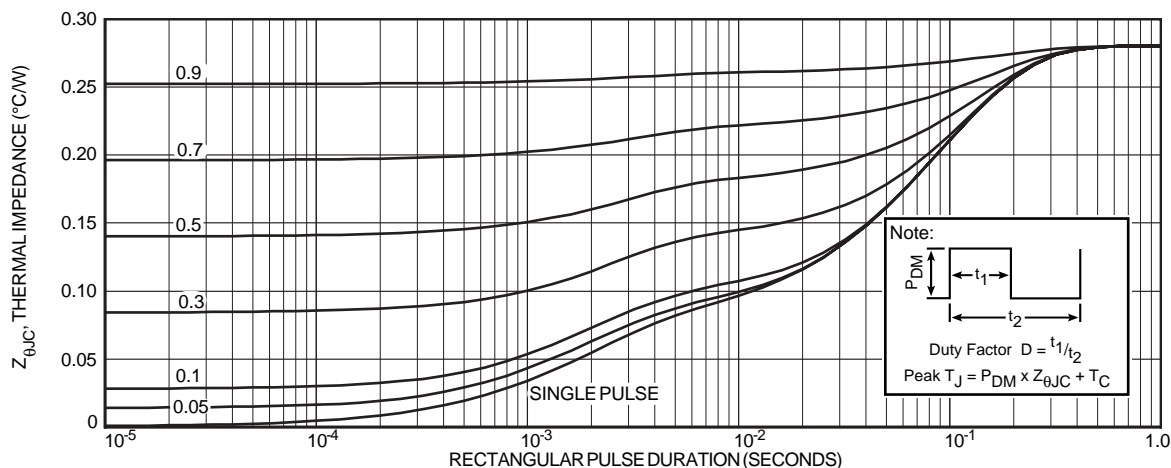


FIGURE 1, MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs PULSE DURATION

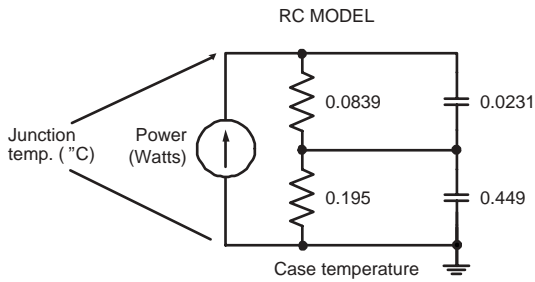


FIGURE 2, TRANSIENT THERMAL IMPEDANCE MODEL

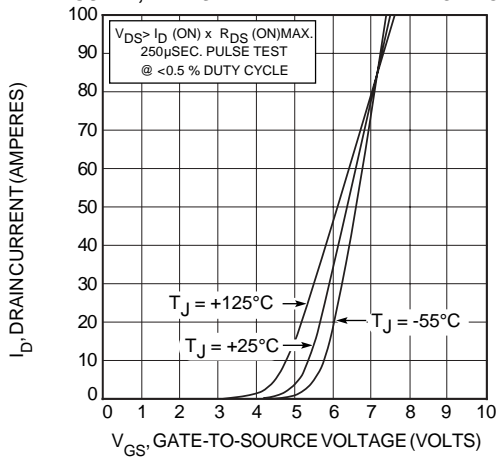


FIGURE 4, TRANSFER CHARACTERISTICS

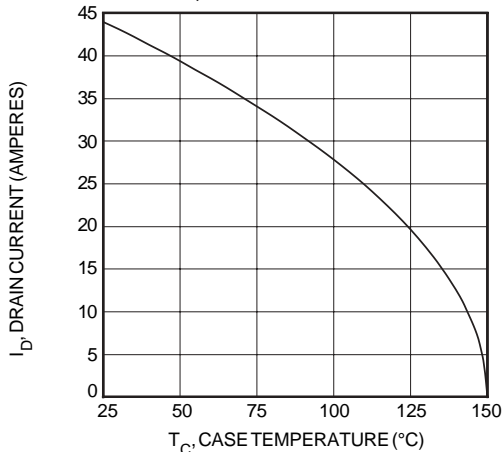


FIGURE 6, MAXIMUM DRAIN CURRENT vs CASE TEMPERATURE

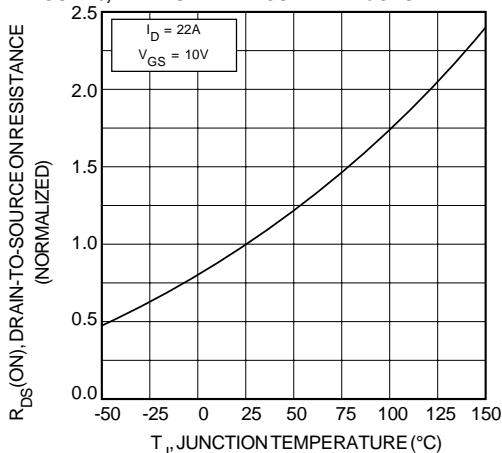


FIGURE 8, ON-RESISTANCE vs. TEMPERATURE

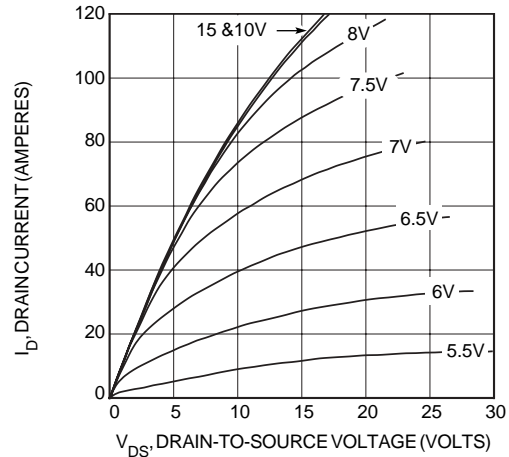


FIGURE 3, LOW VOLTAGE OUTPUT CHARACTERISTICS

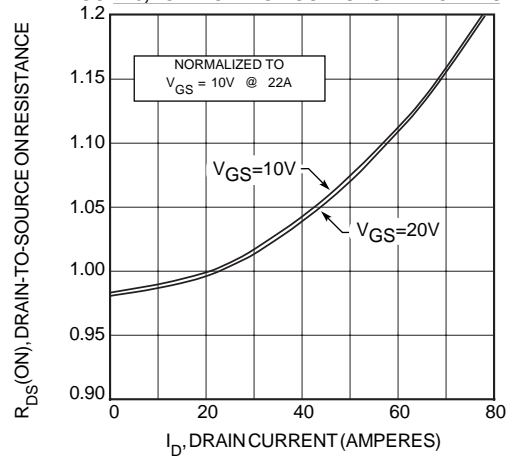


FIGURE 5,  $R_{DS}(ON)$  vs DRAIN CURRENT

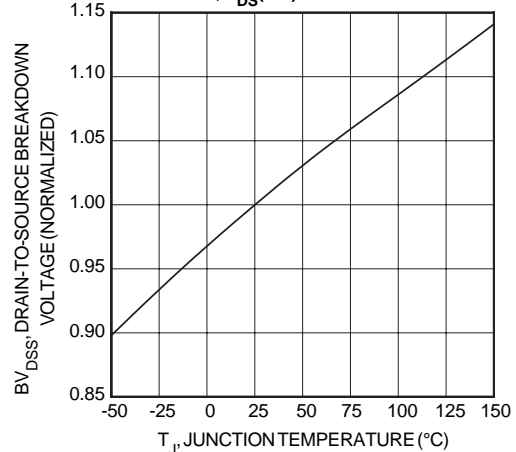


FIGURE 7, BREAKDOWN VOLTAGE vs TEMPERATURE

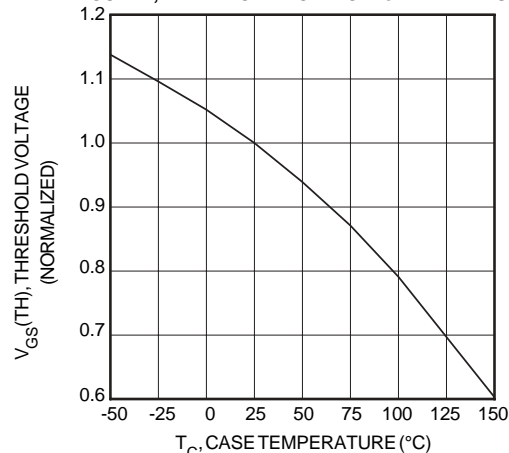


FIGURE 9, THRESHOLD VOLTAGE vs TEMPERATURE

Typical Performance Curves

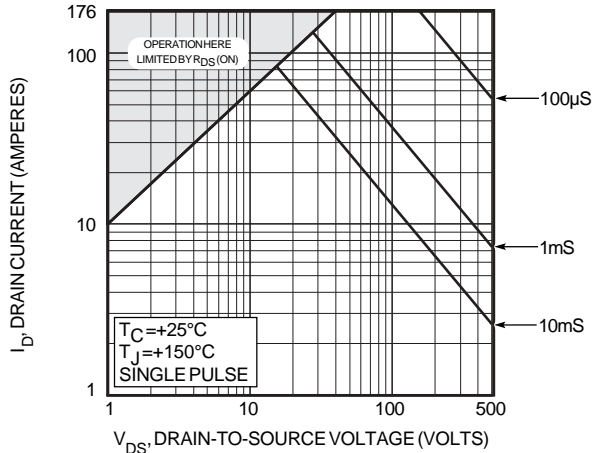


FIGURE 10, MAXIMUM SAFE OPERATING AREA

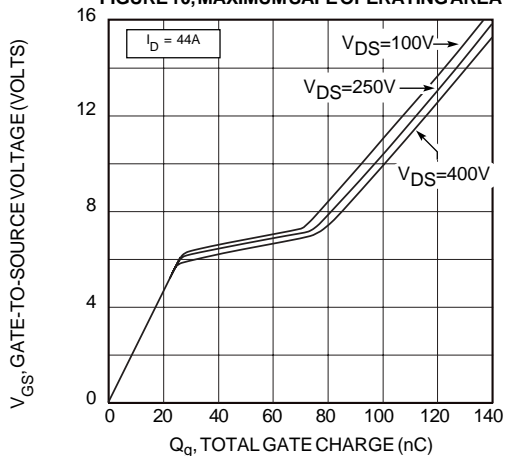


FIGURE 12, GATE CHARGES vs GATE-TO-SOURCE VOLTAGE

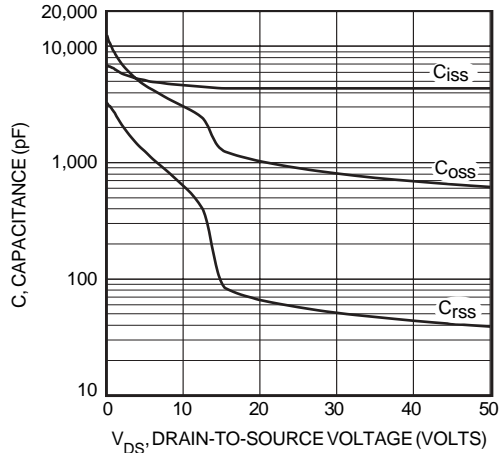


FIGURE 11, CAPACITANCE vs DRAIN-TO-SOURCE VOLTAGE

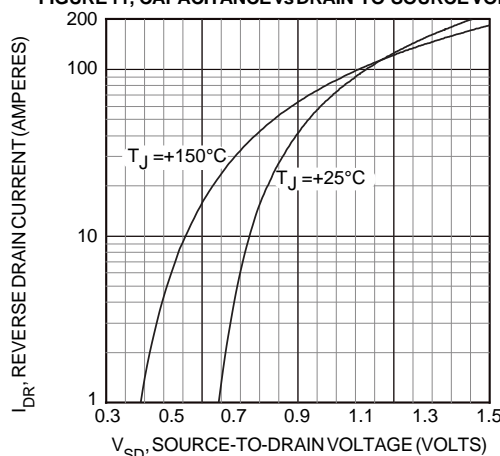


FIGURE 13, SOURCE-DRAIN DIODE FORWARD VOLTAGE

**MAXIMUM RATINGS (UltraFast Recovery Diode)**All Ratings:  $T_C = 25^\circ\text{C}$  unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT5010JLLU2	UNIT
$V_R$	Maximum D.C. Reverse Voltage	600	Volts
$V_{RRM}$	Maximum Peak Repetitive Reverse Voltage		
$V_{RWM}$	Maximum Working Peak Reverse Voltage		
$I_F(AV)$	Maximum Average Forward Current ( $T_C = 80^\circ\text{C}$ , Duty Cycle = 0.5)	30	Amps
$I_F(RMS)$	RMS Forward Current	60	
$I_{FSM}$	Non-Repetitive Forward Surge Current ( $T_J = 45^\circ\text{C}$ , 8.3mS)	320	
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_L$	Lead Temperature: 0.063" from Case for 10 Sec.	300	

**STATIC ELECTRICAL CHARACTERISTICS**

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$V_F$	Maximum Forward Voltage	$I_F = 30\text{A}$		1.8	Volts
		$I_F = 60\text{A}$		1.5	
		$I_F = 30\text{A}, T_J = 150^\circ\text{C}$		1.6	
$I_{RM}$	Maximum Reverse Leakage Current	$V_R = V_R$ Rated		250	$\mu\text{A}$
		$V_R = V_R$ Rated, $T_J = 125^\circ\text{C}$		500	
$C_T$	Junction Capacitance, $V_R = 200\text{V}$		40		pF

**DYNAMIC CHARACTERISTICS**

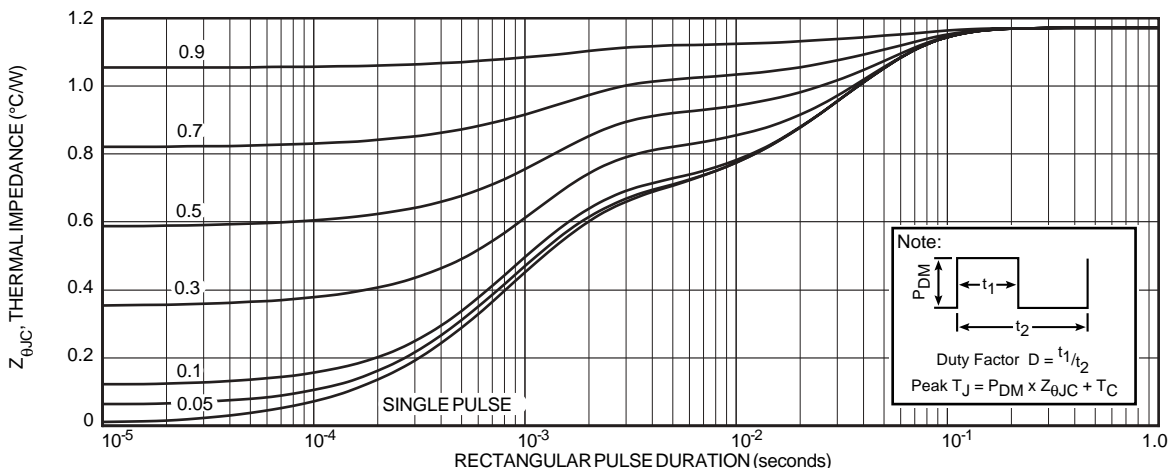
**APT5010JLLU2**

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$t_{rr1}$	Reverse Recovery Time, $I_F = 1.0A$ , $di_F/dt = -15A/\mu S$ , $V_R = 30V$ , $T_J = 25^\circ C$		50	65	nS
$t_{rr2}$	Reverse Recovery Time		50		
$t_{rr3}$	$I_F = 30A$ , $di_F/dt = -240A/\mu S$ , $V_R = 350V$		80		
$t_{fr1}$	Forward Recovery Time		155		
$t_{fr2}$	$I_F = 30A$ , $di_F/dt = 240A/\mu S$ , $V_R = 350V$		155		
$I_{RRM1}$	Reverse Recovery Current		4	10	
$I_{RRM2}$	$I_F = 30A$ , $di_F/dt = -240A/\mu S$ , $V_R = 350V$		7.5	15	
$Q_{rr1}$	Recovery Charge		100		nC
$Q_{rr2}$	$I_F = 30A$ , $di_F/dt = -240A/\mu S$ , $V_R = 350V$		300		
$V_{fr1}$	Forward Recovery Voltage		5		Volts
$V_{fr2}$	$I_F = 30A$ , $di_F/dt = 240A/\mu S$ , $V_R = 350V$		5		
$diM/dt$	Rate of Fall of Recovery Current		400		A/ $\mu S$
	$I_F = 30A$ , $di_F/dt = -240A/\mu S$ , $V_R = 350V$ (See Figure 10)		200		

**THERMAL AND MECHANICAL CHARACTERISTICS**

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance			1.17	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance			20	
$W_T$	Package Weight		1.03		oz.
			29.2		gm.

APT Reserves the right to change, without notice, the specifications and information contained herein.



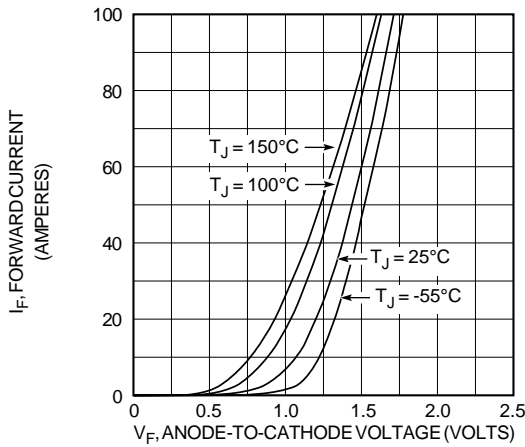


Figure 2, Forward Voltage Drop vs Forward Current

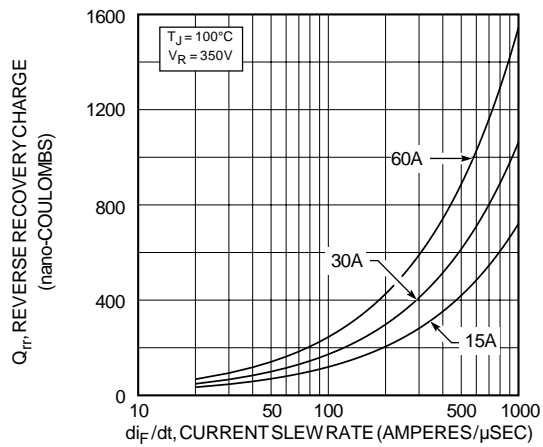


Figure 3, Reverse Recovery Charge vs Current Slew Rate

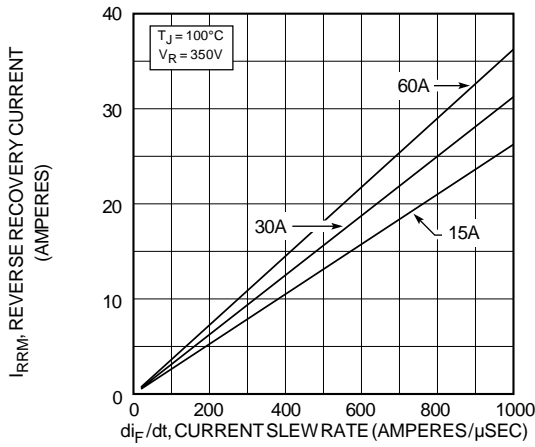


Figure 4, Reverse Recovery Current vs Current Slew Rate

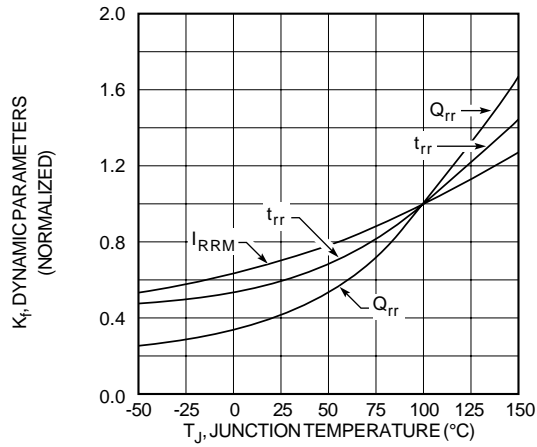


Figure 5, Dynamic Parameters vs Junction Temperature

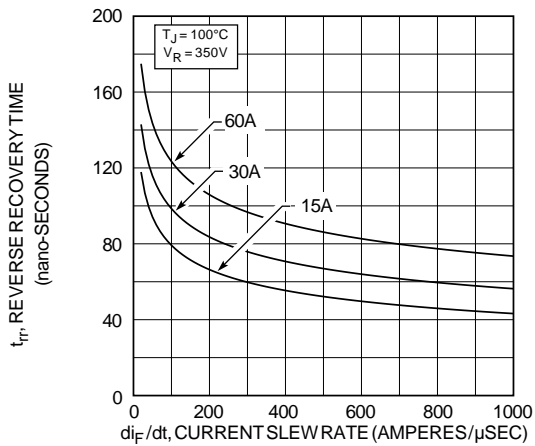


Figure 6, Reverse Recovery Time vs Current Slew Rate

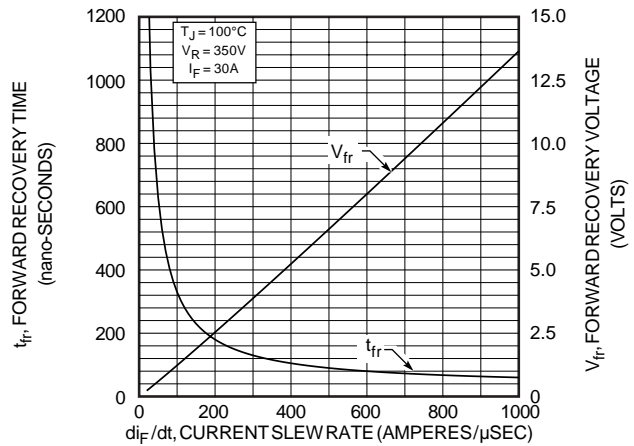


Figure 7, Forward Recovery Voltage/Time vs Current Slew Rate

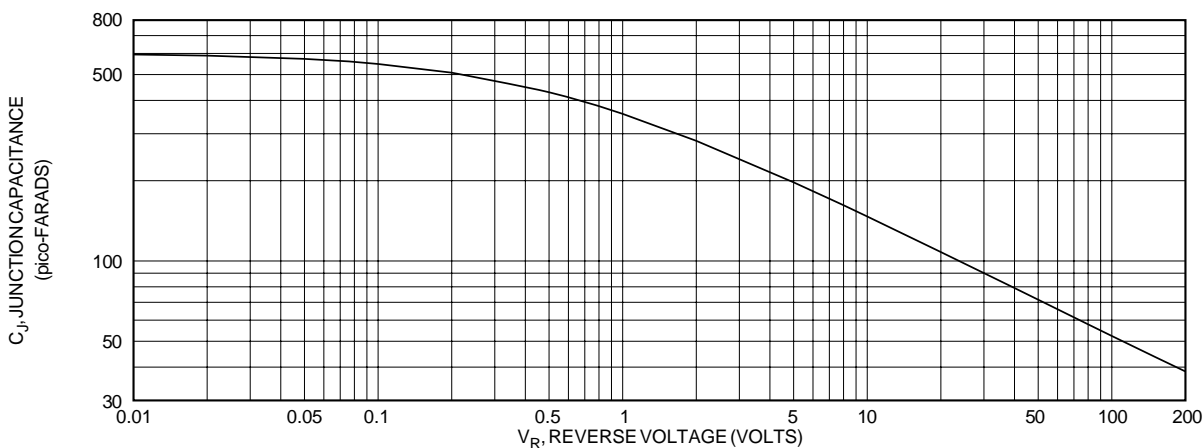


Figure 8, Junction Capacitance vs Reverse Voltage

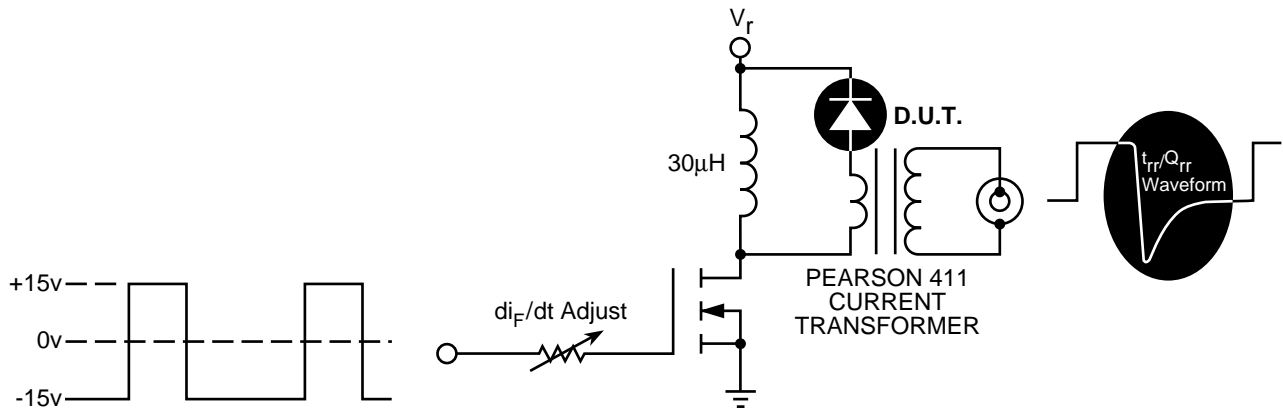


Figure 22, Diode Reverse Recovery Test Circuit and Waveforms

1  $I_F$  - Forward Conduction Current

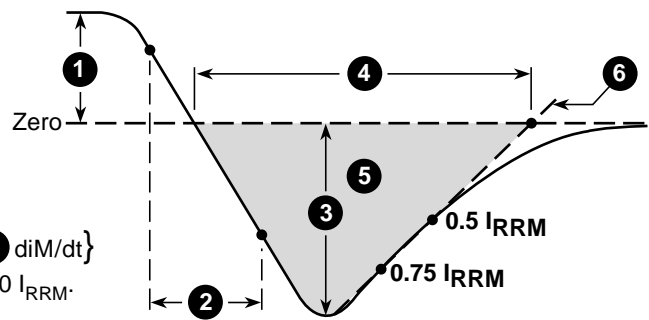
2  $di_F/dt$  - Current Slew Rate, Rate of Forward Current Change Through Zero Crossing.

3  $I_{RRM}$  - Peak Reverse Recovery Current.

4  $t_{rr}$  - Reverse Recovery Time Measured from Point of  $I_F$  Current Falling Through Zero to a Tangent Line {6  $diM/dt$ } Extrapolated Through Zero Defined by 0.75 and 0.50  $I_{RRM}$ .

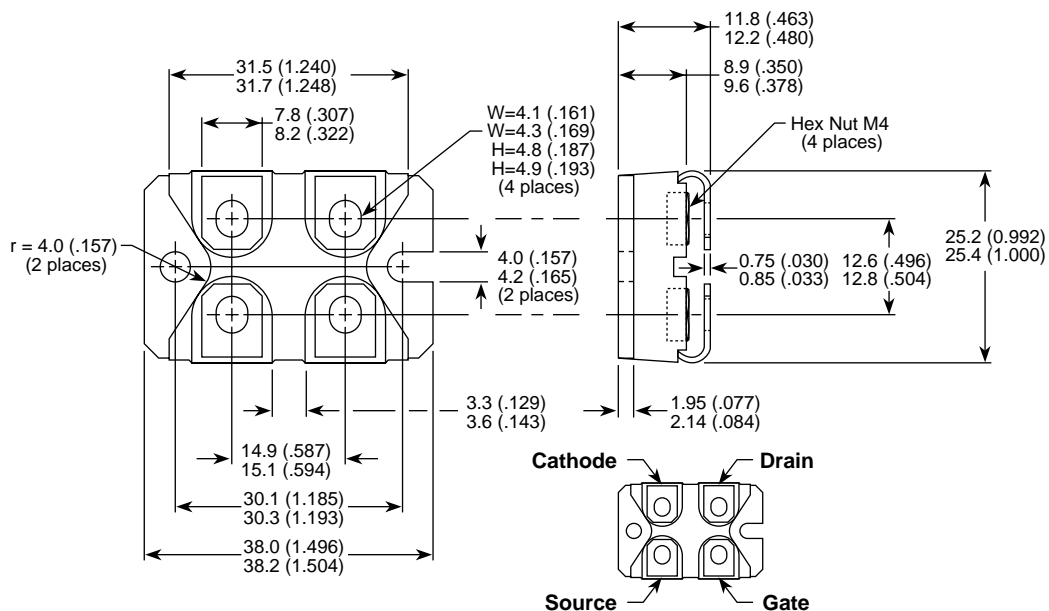
5  $Q_{rr}$  - Area Under the Curve Defined by  $I_{RRM}$  and  $t_{rr}$ .

6  $diM/dt$  - Maximum Rate of Current Change During the Trailing Portion of  $t_{rr}$ .



$$Q_{rr} = 1/2 (t_{rr} \cdot I_{RRM})$$

Figure 23, Diode Reverse Recovery Waveform and Definitions



Dimensions in Millimeters and (Inches)

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UL "UL Recognized" File No. E145592

APT's products are covered by one or more of U.S. patents 4,895,810 5,045,903 5,089,434 5,182,234 5,019,522

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